



Test Report Number: BTF230228R00104

RF Exposure Report

For

Applicant Name: Shenzhen annengxin technology co.,ltd
Address: Floor 3, Building 13, Futing Industrial Park, Fucheng Street,
Longhua District, Shenzhen, Guangdong, China
EUT Name: Smart Switch
Brand Name: N/A
Model Number: AN-WDS01
Series Model Number: Refer to section 2

Issued By

Company name: BTF Testing Lab (Shenzhen) Co., Ltd.
Address: F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park,
Tantou Community, Songgang Street, Bao'an District, Shenzhen,
China

Report number: BTF230228R00104
Test standards: 47 CFR Part 2 Subpart J Section 2.1091
FCC ID: 2BAF7-ANWDS01
Test conclusion: Pass
Date of sample receipt: 2025-04-16
Test date: 2025-04-16 to 2025-05-06
Date of issue: 2025-05-08

Test by: Sean He
Sean He / Tester

Prepared by: Chris Liu

Chris Liu/ Project engineer



Olic Huang

Olic Huang/EMC manager

Note: All the test results in this report only related to the testing samples. Which can be duplicated completely for the legal use with approval of applicant; it shall not be reproduced except in full without the written approval of BTF Testing Lab (Shenzhen) Co., Ltd., All the objections should be raised within thirty days from the date of issue. To validate the report, you can contact us.

Revision History		
Version	Issue Date	Revisions Content
R_V0	2025-05-08	Original
Note:		Once the revision has been made, then previous versions reports are invalid.

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1. Introduction

1.1 Identification of Testing Laboratory

Company Name:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Phone Number:	+86-0755-23146130
Fax Number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Test Location:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	F101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
Description:	All measurement facilities used to collect the measurement data are located at F101,201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, China
FCC Registration Number:	518915
Designation Number:	CN1409

1.3 Announcement

- (1) The test report reference to the report template version v0.
- (2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
- (3) The test report is invalid if there is any evidence and/or falsification.
- (4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
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- (6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.

2. Product Information

2.1 Application Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.2 Manufacturer Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.3 Factory Information

Company Name:	Shenzhen annengxin technology co.,ltd
Address:	Floor 3, Building 13, Futing Industrial Park, Fucheng Street, Longhua District, Shenzhen, Guangdong, China

2.4 General Description of Equipment under Test (EUT)

EUT Name	Smart Switch
Under Test Model Name	AN-WDS01
Series Model Name	AN-WS01, AN-WS01L, AN-WCS01, AN-WFS01, AN-WFLS01, AN-WHS01, AN-WHS02, AN-WS02, AN-WS02L, AN-WS03, AN-WS03L, AN-WS04, AN-WS04L
Description of Model name differentiation	Only the model name is different, everything else is the same.
Rating:	Voltage:AC 100-240v 50~60hz Output:400W

3. Test Requirement

The criteria listed in the following table shall be used to evaluate the environment impact of human exposure to radio frequency (RF) radiation as specified in 1.1307(b), Limits for Maximum Permissible Exposure (MPE),

Frequency range (MHz)	Electric field strength(V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500	-	-	f/300	6
1500–100,000	-	-	5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30
30–300	27.5	0.073	0.2	30
300–1500	-	-	f/1500	30
1500–100,000	-	-	1.0	30

Note: f = frequency in MHz

EVALUATION METHOD

Transmission formula: $Pd = (Pout * G) / (4 * \pi * r^2)$

Where

Pd = power density in mW/cm², **Pout** = output power to antenna in mW, **G** = gain of antenna in linear scale;

Pi = 3.1416, **R** = distance between observation point and center of the radiator in cm

3.1 Assessment Result

☒ Passed ☐ Not Applicable

Frequency (MHz)	Type	Conducted Power (dBm)	Maximum Tune-up (dBm)	Gain	Power Density (mW/cm ²)	Limit (mW/cm ²)	Result
2480	BT-EDR	7.09	8.00	1.3	0.0017	1.0000	Pass
2440	BT-BLE	-2.68	-2.00	1.3	0.0002	1.0000	Pass
2412	802.11g	20.50	21.00	1.3	0.0338	1.0000	Pass

Note: The exposure evaluation safety distance is 20cm.



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